

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination 09/788,335 JAFFRAY ET AL.	
	Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B	US-6,385,286 B1	/	05-2002	Fitchard et al.	378/65
C	US-6,318,892 B1	/	11-2001	Suzuki et al.	378/197
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity. Elements of X-Ray Diffraction, Second Edition (Reading, MA: Addison-Wesley, 1978), p. 6-12.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.